

FACULTY OF ENGINEERING

BE II Semester (Main & Backlog) Examination May/June 2018

Subject : Engineering Physics-II

Time : 3 Hours.

Max. Marks: 70

Note : Answer all questions from Part-A & any five questions from Part-B.

PART-A (20 Marks)

- 1 Find the Miller indices of a set of parallel lines which make equal intercepts along the three Axes.
- 2 Write short note on crystal imperfections.
- 3 Write any four assumptions of free electron theory.
- 4 The intrinsic carrier density is $1.5 \times 10^{16}/\text{m}^3$ if the electron and hole motilities are 0.13 and $0.05 \text{m}^2 \text{V}^{-1} \text{s}^{-1}$ calculate the electrical conductivity.
- 5 What is Meissner effect in superconductors.
- 6 Mention the applications of Ferro electric material.
- 7 What is the significance of Hall effect.
- 8 Distinguish between a dielectric material and an insulator.
- 9 What are the advantages of thin films over bulk materials.
- 10 What is the surface to volume ratio at nano-scale.

PART-B (5x10=50 Marks)

11. a) Discuss the determination of lattice constants by powder diffraction method. 6
b) Distinguish between insulator, semiconductor and conductors based on the energy band diagram. 4
12. a) Explain the hysteresis curve of a ferro magnetic materials on the basis of magnetic domains. 5
b) State the Joshepson effect. Explain the properties of superconducting materials. 5
13. a) What is Hall effect? Obtain the expression for Hall coefficient. 5
b) Explain the crystal structure of the Barium Titanate. 5
14. a) Explain the principle and the technique of X-ray fluorescence. 5
b) Describe any one type of thermal evaporation technique with neat diagram. 5
15. a) Explain the synthesis of nano particles using Sol Gel method. 6
b) Write the applications of nano particles. 4
16. a) Explain the frequency and temperature dependence of dielectric polarization. 6
b) What are the salient feature of kronig-Penny model? 4
17. a) Obtain an expression for the conductivity of an n-type semiconductor. 5
b) Explain construction and working of Scanning Electron Microscope(SEM). 5
